TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (Ultra High speed U-MOSIII)

# **TPCP8103-H**

High Efficiency DC / DC Converter Applications
Notebook PC Applications
Portable Equipment Applications
CCFL Inverter Applications

- Small footprint due to a small and thin package
- · High speed switching
- Small gate charge: QSW = 6.5 nC (typ.)
- Low drain-source ON-resistance: RDS (ON) = 31 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 10 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = -40 \text{V)}$
- Enhancement mode:  $V_{th} = -0.8 \text{ to } -2.0 \text{ V } (V_{DS} = -10 \text{ V}, I_D = -1 \text{mA})$

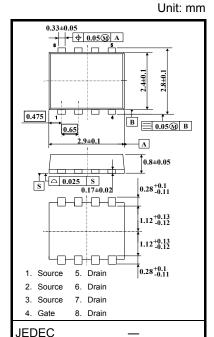
# **Absolute Maximum Ratings (Ta = 25°C)**

Characte	eristic	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-40	V	
Drain-gate voltage (R	GS = 20 kΩ)	$V_{DGR}$	-40	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	ID	-4.8	Α	
Diam current	Pulsed (Note 1)	$I_{DP}$	-19.2		
Drain power dissipati	on $(t = 5 s)$ (Note 2a)	$P_{D}$	1.68	W	
Drain power dissipati	on (t = 5 s) (Note 2b)	P <sub>D</sub>	0.84	W	
Single-pulse avalance	ne energy (Note 3)	E <sub>AS</sub>	10.7	mJ	
Avalanche current		I <sub>AR</sub>	-4.8	Α	
Repetitive avalanche	energy c=25°C) (Note 4)	E <sub>AR</sub>	0.09	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature	range	T <sub>stg</sub>	-55 to 150	°C	

Note: For Notes 1 to 4, refer to the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

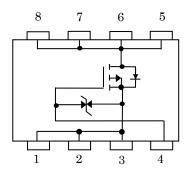
This transistor is an electrostatic-sensitive device. Handle with care.



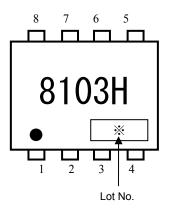
Weight: 0.017 g (typ.)

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## **Circuit Configuration**



2-3V1K



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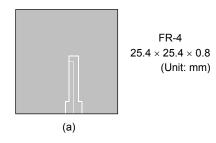
#### **Thermal Characteristics**

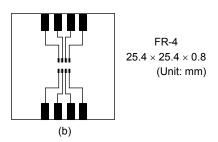
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to ambient $(t = 5 s)$ (Note 2a)	R <sub>th (ch-a)</sub>	74.4	°C/W
Thermal resistance, channel to ambient (t = 5 s) (Note 2b)	R <sub>th (ch-a)</sub>	148.8	°C/W

Note 1: The channel temperature should not exceed 150°C during use.

Note 2: (a) Device mounted on a glass-epoxy board (a)

(b) Device mounted on a glass-epoxy board (b)





Note 3:  $V_{DD} = -24~V,~T_{Ch} = 25^{\circ}C$  (initial), L = 0.5 mH, R<sub>G</sub> = 25  $\Omega,~I_{AR} = -4.8A$ 

Note 4: Repetitive rating: pulse width limited by max channel temperature

Note 5: \* Weekly code: (Three digits)

Week of manufacture
(01 for first week of the year, continuing up to 52 or 53)

Year of manufacture
(The last digit of the calendar year)



Electrical Characteristics (Ta = 25°C)

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Ch	Characteristic		Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cutoff curre	nt	I <sub>DSS</sub>	V <sub>DS</sub> = -40 V, V <sub>GS</sub> = 0 V	_	_	-10	μА
Orain-source breakdown voltage		V <sub>(BR) DSS</sub>	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$ -40	_	_	V	
Dialii-source brea	akdowii voltage	V <sub>(BR) DSX</sub>	$I_D = -10 \text{ mA}, V_{GS} = -20 \text{ V}$	-20			v
Gate threshold vo	threshold voltage		$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$	-0.8	_	-2.0	٧
Drain-source ON	rosistanco	Pro (OV)	$V_{GS} = -4.5 \text{ V}, I_D = -2.4 \text{ A}$	_	42	54	mΩ
Dialii-source Oiv	-iesistarice	R <sub>DS</sub> (ON)	$V_{GS} = -10 \text{ V}, I_D = -2.4 \text{ A}$	_	31	40	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -2.4 \text{ A}$	5	10	_	S
Input capacitance		C <sub>iss</sub>		_	800	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	115	_	
Output capacitance		C <sub>oss</sub>		_	165	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $-10 \text{ V}$ $O$	_	6.5	_	- ns
	Turn-on time	t <sub>on</sub>		_	12.5	_	
	Fall time	tf		_	9	_	
	Turn-off time	t <sub>off</sub>		_	37	_	
Total gate charge		0	$V_{DD} \simeq -32 \text{ V}, V_{GS} = -10 \text{ V},$ $I_D = -4.8 \text{ A}$	_	19	_	
(gate-source plus	gate-drain)	Qg	$Q_g$ $V_{DD} \simeq -32 \text{ V, } V_{GS} = -5 \text{ V,}$ $I_D = -4.8 \text{ A}$ — 11		11		nC
Gate-source charge 1		Q <sub>gs1</sub>	$V_{DD} \simeq -32 \text{ V, } V_{GS} = -10 \text{ V,}$ $I_{D} = -4.8 \text{ A}$	_	1.5	_	-
Gate-drain ("Miller") charge		Q <sub>gd</sub>		_	5.5	_	
Gate switch charge		Q <sub>SW</sub>	] -	_	6.5	_	

# Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	I <sub>DRP</sub>	_	_	_	-19.2	Α
Forward voltage (diode)			$V_{DSF}$	$I_{DR} = -4.8 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.2	V

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